







Corn yield on a LOW P-testing soil as affected by starter, deep-band, and broadcast P.						
Tillage for P Placement / Method				thod		
Corn	Soybean	None	Starter	DB	Bdct.	
	Yield (bu/acre)					
No-till	No-till	97	140			
F. Cult.	S. Disk	102	153	146	166	
Strip-till	No-till	101	152	148		
Chisel	Chisel	103	154		166	
	Average:	101	150			
Soil Tes	t P = (3 to 2	0) ppm	Bray P ₁	6-	yr avg	
2/23/2004						

Soybean yield on a LOW P-testing soil as						
affected	by the resid	dual effe	ects of s	tarter,	deep-	
ban	d, and broa	dcast P	applied	to cor	n.	
Tillaç	ge for	PF	lacemer	nt / Me	thod	
Corn	Soybean	None	Starter	DB	Bdct.	
Yield (bu/acre)						
No-till	No-till	34	48			
F. Cult.	S. Disk	36	49	49	53	
Strip-till	No-till	37	50	48		
Chisel	Chisel	32	50		53	
	Average:	35	49			
Soil Test P = (5 to 19) ppm Bray P_1 5-yr avg.						
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Corn yield on a HIGH P-testing soil as affected by starter, deep-band, and broadcast P.						
Tillaç	ge for	ΡF	P Placement / Method			
Corn	Soybean	None	Starter	DB	Bdct.	
	Yield (bu/acre)					
No-till	No-till	156	160			
F. Cult.	S. Disk	161	168	165	176	
Strip-till	No-till	164	168	165		
Chisel	Chisel	165	170		176	
	Average:	162	166			
Soil Test	P = (10 to 2	7) ppm	Bray P ₁	6	δ-yr avg.	
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Soybean yield on a HIGH P-testing soil as affected by the residual effects of starter, deepband, and broadcast P applied to corn. **Tillage** for P Placement / Method Soybean Corn None Starter DB Bdct. Yield (bu/acre) - -- -No-till No-till 50 52 ___ F. Cult. S. Disk 54 55 54 55 Strip-till No-till 53 52 54 __ Chisel Chisel 52 55 55 __ 52 54 Average: Soil Test P = (14 to 30) ppm Bray P_1 5-yr avg 2/23/2004



Economic return to P by corn as							
affecte	affected by STP level and rate and						
metho	d of P appli	cation to	corn.†				
	P Soil Test P Level						
Rate	Method	VL-L	High				
- Ib P ₂ O ₅ /A/yr -		\$/A/yr					
50 (40)	Starter	95	-5				
50 (40)	Deep band	88	-12				
100 (80)	Broadcast	120	+4				
† Six site-years							
2/23/2004							

Economic return to P by soybeans as						
affected	by STP lev	vel and r	ate and			
method	l of P appli	cation to	corn.†			
	P	Soil Test	P Level			
Rate	Method	VL-L	High			
- lb P ₂ O ₅ /A/yr -		\$/A/yr				
50 (40)	Starter	76	6			
50 (40)	Deep band	63	4			
100 (80)	Broadcast	100	10			
† Five site-years						
2/23/2004			<u> </u>			

















Soil test P (0–2 inch) on a LOW P-testing soil as affected by tillage and P placement.

Tillensfer					
i mage for		P Placement / Method			
Corn	Soybean	None	Starter*	DB*	Bdct.**
			soil test F	o (ppm	I)
No-till	No-till	5	14		
F. Cult.	S. Disk	6	13	6	36
Strip-till	No-till	4	13	6	
Chisel	Chisel	4	10		18
* Total of 1	50 lb P ₂ O ₅ /A a	pplied 19	97, 1999, ar	nd 2001.	2002
** Total of 3	00 lb P ₂ O ₅ /A a	pplied 19	97, 1999, ar	nd 2001.	
2/23/2004					

Soil test P (0–2 inch) on a HIGH P-testing soil							
as ai		maye a		Ceme	in.		
Tillage for P Placement / Method				thod			
Corn	Soybean	None	Starter*	DB*	Bdct.**		
	soil test P (ppm)						
No-till	No-till	15	29				
F. Cult.	S. Disk	12	26	18	50		
Strip-till	No-till	12	24	17			
Chisel	Chisel	15	21		35		
* Total of 120 lb P ₂ O ₅ /A applied 1997, 1999, and 2001. 2002							
** Total of 240 lb P ₂ O ₅ /A applied 1997, 1999, and 2001.							
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- At the low P-testing site, economic return to P was greatest when broadcast, intermediate when placed in the seed furrow, and lowest when deep-banded.
- At the high P-testing site economic return to P across years did not occur regardless of placement method.
- Corn and soybean yields were highly correlated to STP on the low-testing site.

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Conclusions cont.

- STP in the surface 2 inches was greatly influenced by P placement and slightly affected by tillage.
- The potential for P loss to surface water is least for the deep-band treatments, regardless of tillage, and greatest for broadcast P, especially in the one-pass tillage system.

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THANK YOU

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